

## Silicon N-Channel Power MOSFET

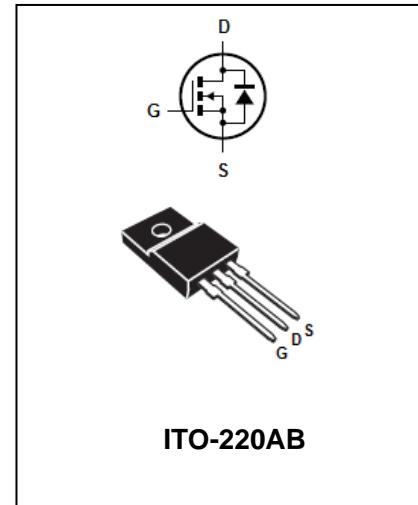
BL10N60F

### FEATURES

- Fast Switching
- ESD Improved Capability
- Low Gate Charge (Typical Data:38nC)
- Low Reverse transfer capacitances(Typical:15pF)
- 100% Single Pulse avalanche energy Test



Lead-free



### APPLICATIONS

- Power switch circuit of adaptor and charger.

**MAXIMUM RATING @ Ta=25°C unless otherwise specified**

Symbol	Parameter	Value	Units
V <sub>DSS</sub>	Drain-to-Source voltage	600	V
V <sub>GS</sub>	Gate -Source voltage	±30	V
I <sub>D</sub>	Continuous Drain current Continuous Drain current Tc=100°C	10 6.4	A
I <sub>DM</sub> <sup>a1</sup>	Pulsed Drain current	40	A
dv/dt <sup>a3</sup>	Peak Diode Recovery dv/dt	5.0	V/ns
P <sub>D</sub>	Power Dissipation	50	W
V <sub>ESD(G-S)</sub>	Gate source ESD(HBM-C=100pF,R=1.5kΩ)	4000	V
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and StorageTemperature	150, -55 to +150	°C
T <sub>L</sub>	Maximum Temperature for Soldering	300	°C

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## ELECTRICAL CHARACTERISTICS @ Ta=25°C unless otherwise specified

<b>OFF Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Test conditions</b>	<b>MIN</b>	<b>TYP</b>	<b>MAX</b>	<b>UNIT</b>
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	600	-	-	V
Bvdss Temperature Coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	I <sub>D</sub> =250uA, Reference 25°C	-	0.74	-	V/°C
Drain to Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V	-	-	25	uA
Gate to Source Forward Leakage	I <sub>GSS(F)</sub>	V <sub>GS</sub> =30V	-	-	10	uA
Gate to Source ReverseLeakage	I <sub>GSS(R)</sub>	V <sub>GS</sub> =-30V	-	-	-10	μA

<b>ON Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Test conditions</b>	<b>MIN</b>	<b>TYP</b>	<b>MAX</b>	<b>UNIT</b>
Drain-to-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =3mA	-	0.65	0.75	Ω
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.0	-	4.0	V

<b>Dynamic Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Test conditions</b>	<b>MIN</b>	<b>TYP</b>	<b>MAX</b>	<b>UNIT</b>
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =15V, I <sub>D</sub> =5.0A	-	11	-	S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz	-	1758	-	pF
Output Capacitance	C <sub>oss</sub>		-	153	-	
Reserse Transfer Capacitance	C <sub>rss</sub>		-	15	-	

<b>Resistive Switching Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Test conditions</b>	<b>MIN</b>	<b>TYP</b>	<b>MAX</b>	<b>UNIT</b>
Turn-on Delay Time	t <sub>d(ON)</sub>	I <sub>D</sub> =10.0A, V <sub>DD</sub> =300V, V <sub>GS</sub> =10V, R <sub>G</sub> =4.7Ω	-	20	-	ns
Rose Time	t <sub>r</sub>		-	20	-	
Turn-Off Delay Time	t <sub>d(OFF)</sub>		-	55	-	
Fall Time	t <sub>f</sub>		-	30	-	

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Total Gate Charge	Qg	$I_D=10.0A, V_{DD}=300V, V_{GS}=10V$	-	38		nC
Gate to Source Charge	Qgs		-	8.7		
Gate to Drain ("Miller") Charge	Qgd		-	15		

Source-Drain Diode Characteristics							
Parameter	Symbol	Test conditions	MIN	TYP	MAX	UNIT	
Continuous Source Current(Body Diode)	$I_S$	$T_a=25^\circ C$	-	-	10	A	
Maximum Pulsed Current(Body Diode))	$I_{SM}$		-	-	40	A	
Diode Forward Voltage	$V_{SD}$	$I_S=10.0A, V_{GS}=0V$	-		1.5	V	
Reserse Recovery Time	trr	$I_F=10.0A, T_j=25^\circ C, dI_F/dt=100A/us, V_{GS}=0V$	-	434	-	ns	
Reserse Recovery Charge	Qrr		-	2.6	-	nC	

Parameter	Symbol	TYP	UNIT
Junction-to-Case	$R_{\theta JC}$	2.5	°C/W
Junction-to-Ambient	$R_{\theta JA}$	100	°C/W

Gate –source Zener Diode						
Parameter	Symbol	Test conditions	Rating			UNIT
			MIN	TYP	MAX	
Gate-source breakdown voltage	$V_{GSO}$	$IGS=\pm 1mA$ (Open Drain)	20	-	-	V

The built-in-back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

a1: Repetitive rating; pulse width limited by maximum junction temperature

a2:  $L=10.0mH, I_D=12.6A, Start T_j=25^\circ C$ a3:  $I_{SD} = 10A, di/dt \leq 100A/us, V_{DD} \leq BV_{DS}, Start T_j=25^\circ C$

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TYPICAL CHARACTERISTICS @  $T_a=25^\circ\text{C}$  unless otherwise specified

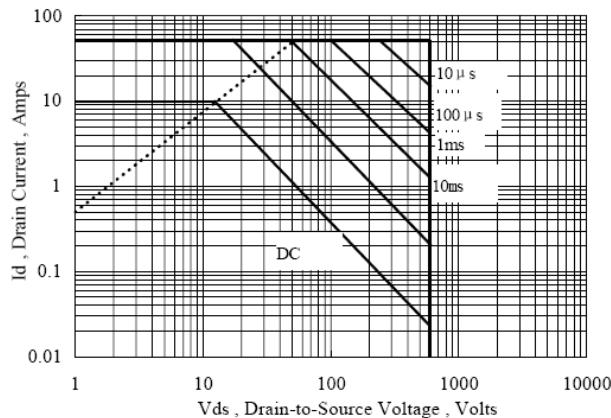


Figure 1 Maximum Forward Bias Safe Operating Area

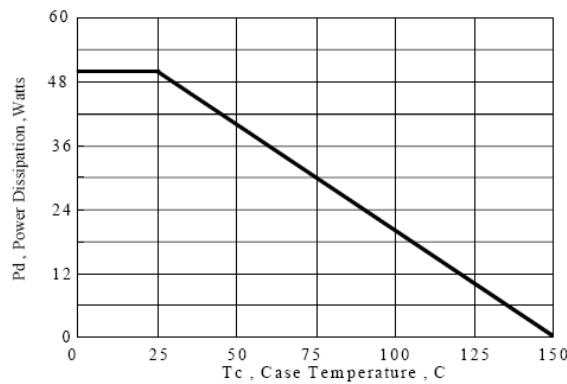


Figure 2 Maximum Power Dissipation vs Case Temperature

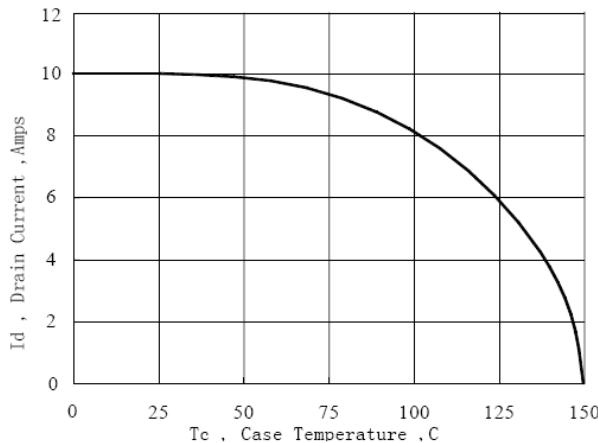


Figure 3 Maximum Continuous Drain Current vs Case Temperature

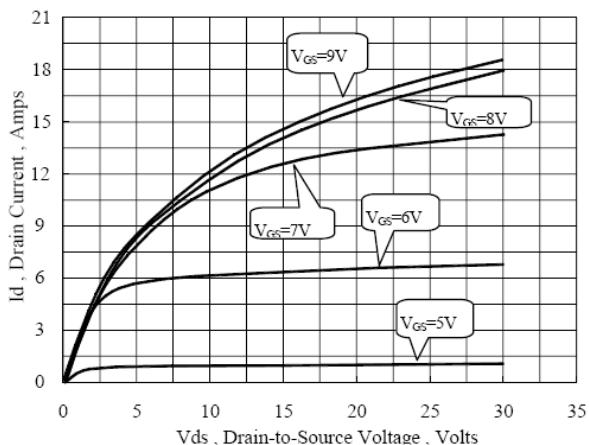


Figure 4 Typical Output Characteristics

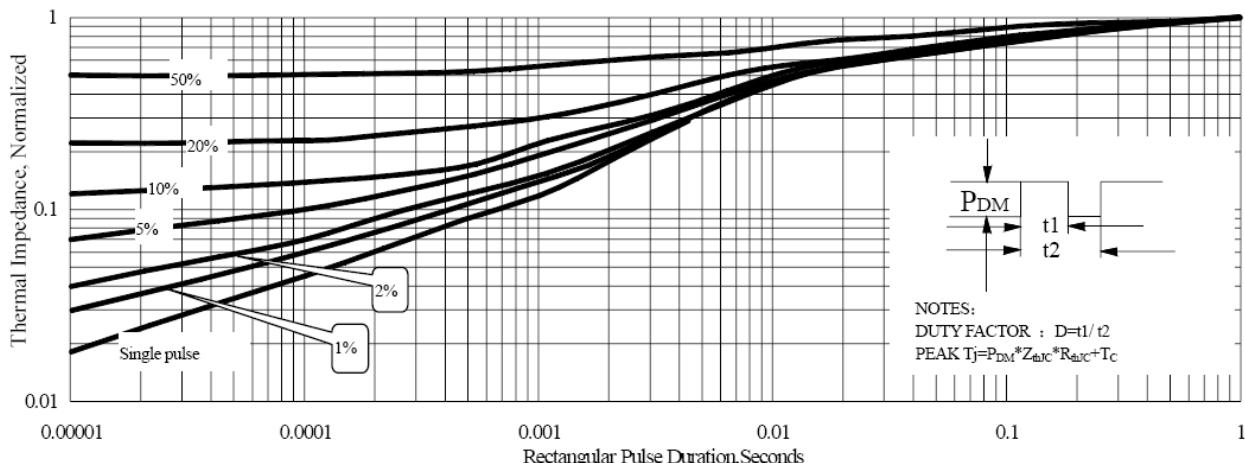
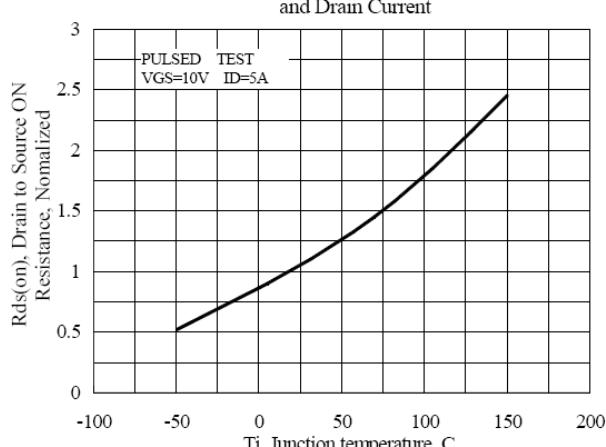
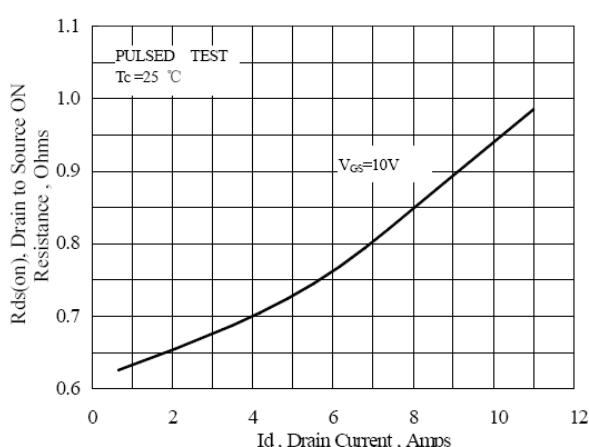
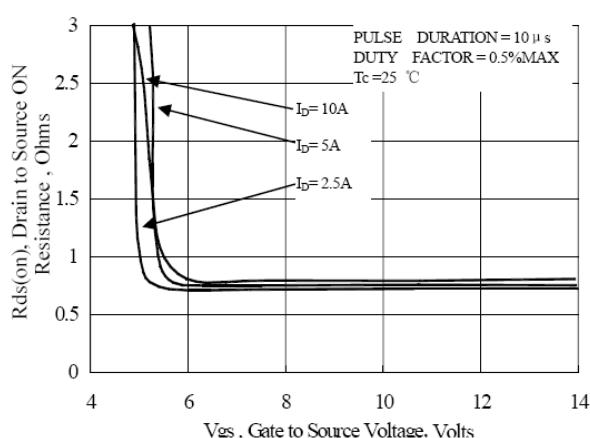
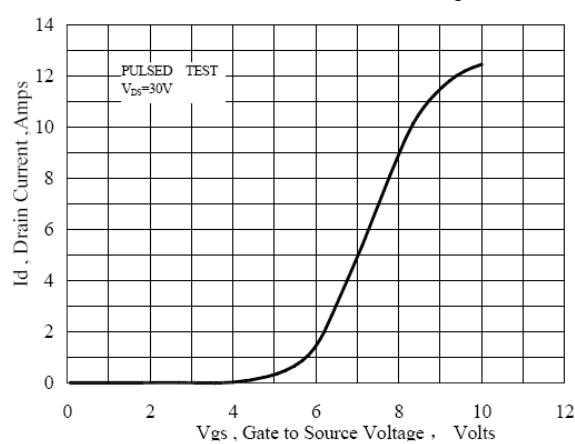
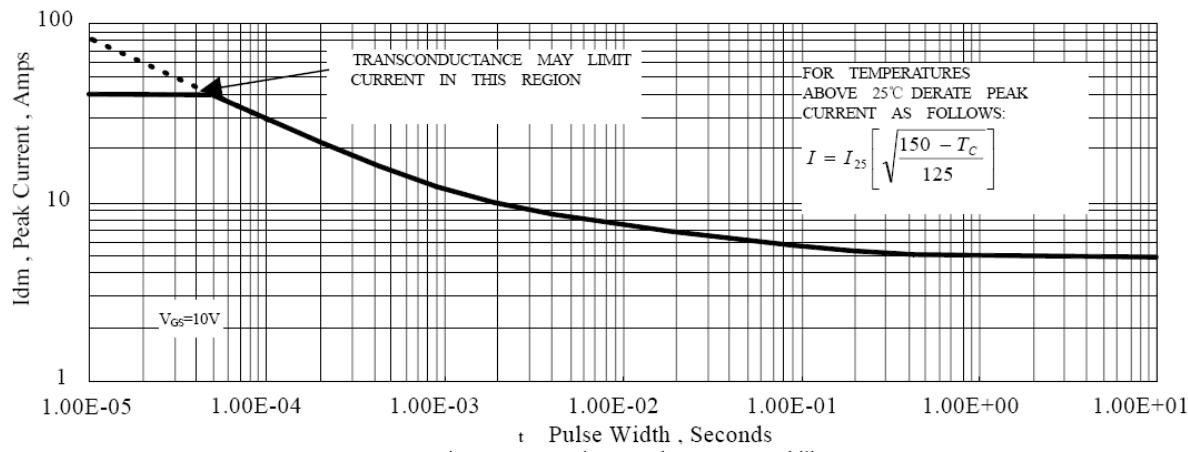


Figure 5 Maximum Effective Thermal Impedance, Junction to Case

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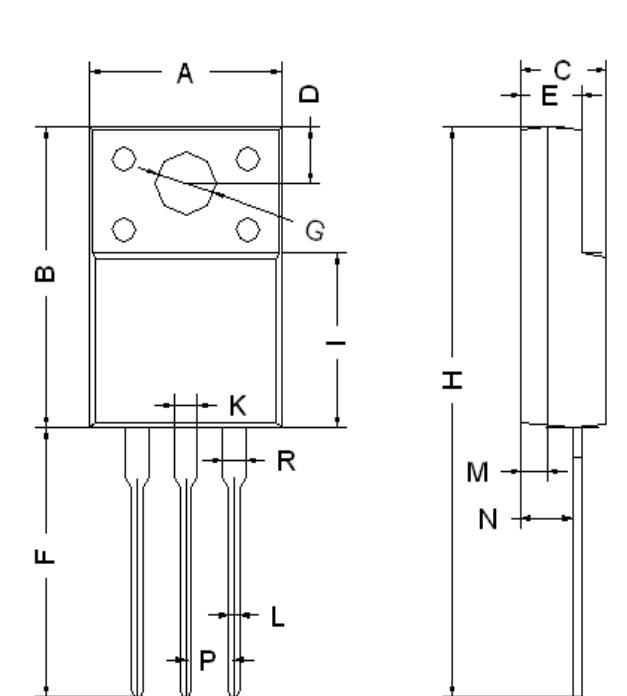
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### PACKAGE OUTLINE

Plastic surface mounted package

ITO-220AB



ITO-220AB		
Dim	Min	Max
A	9.90	10.30
B	14.80	15.20
C	4.50	Typical
D	2.70	Typical
E	2.80	3.30
F	13.00	13.60
G	3.2	Typical
H	28.00	28.60
I	7.90	8.90
J	0.50	Typical
L	0.70	0.90
M	1.40	Typical
N	2.60	2.80
P	2.45	2.65
K/R	1.20	Typical

All Dimensions in mm